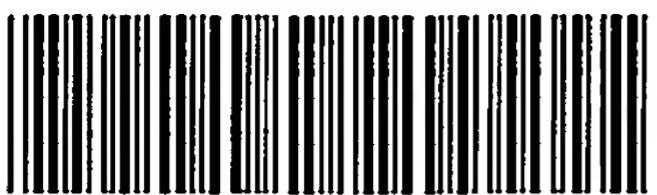


Search Notes



Application/Control No.

10/607,612

Examiner

Binh X. Tran

**Applicant(s)/Patent under
Reexamination**

PUPPO ET AL.

Art Unit

1765

SEARCHED

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)